

*“Structural characterization of SnS crystals formed by chemical vapour deposition”.* Mehta AN, Zhang H, Dabral A, Richard O, Favia P, Bender H, Delabie A, Caymax M, Houssa M, Pourtois G, Vandervorst W, Journal of microscopy  
T2 - 20th International Conference on Microscopy of Semiconducting Materials, (MSM), A R 09-13, 2017, Univ Oxford, Univ Oxford, Oxford, ENGLAND **268**, 276 (2017).  
<http://doi.org/10.1111/JMI.12652>